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Pages: 266 - 280

[PDF Full-Text (372 KB)] [Abstract]

2. Low-speed scan testing of charge-sharing faults for CMOS domino circuits

Cheng, C.H.; Jone, W.B.; Chang, S.C.; Wang, J.S.;

Electronics Letters, Volume: 36, Issue: 20, 28 Sep 2000

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[PDF Full-Text (252 KB)] [Abstract]

3 Low-speed scan testing of charge-sharing faults for CMOS domino

Cheng, C.H.; Jone, W.B.; Wang, J.S.; Chang, S.C.;

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[PDF Full-Text (472 KB)] **IEEE CNF** [Abstract]

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[PDF Full-Text (1135 KB)] IEEE CNF [Abstract]

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